

Resource Summary Report

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JEOL: JCM-7000 NeoScope Benchtop Scanning Electron Microscope (SEM)

RRID:SCR_020180

Type: Tool

Proper Citation

JEOL: JCM-7000 NeoScope Benchtop Scanning Electron Microscope (SEM)
(RRID:SCR_020180)

Resource Information

URL: <https://www.jeolusa.com/PRODUCTS/Scanning-Electron-Microscopes-SEM/Benchtop/NeoScope-Benchtop-SEM>

Proper Citation: JEOL: JCM-7000 NeoScope Benchtop Scanning Electron Microscope (SEM) (RRID:SCR_020180)

Description: Scanning electron microscope that is equipped with large chamber, high and low vacuum modes, secondary and backscatter electron detectors, real time 3D imaging, highly advanced auto functions and option to add fully embedded EDS with real time, Live, analysis.

Resource Type: instrument resource

Keywords: Jeol, JEOL, Scanning Electron Microscope, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: JEOL: JCM-7000 NeoScope Benchtop Scanning Electron Microscope (SEM)

Resource ID: SCR_020180

Alternate IDs: Model_Number_JCM-7000 NeoScope Benchtop

Record Creation Time: 20220129T080349+0000

Record Last Update: 20260912T195931+0000

Ratings and Alerts

No rating or validation information has been found for JEOL: JCM-7000 NeoScope Benchtop Scanning Electron Microscope (SEM).

No alerts have been found for JEOL: JCM-7000 NeoScope Benchtop Scanning Electron Microscope (SEM).

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.